

Features

- AQC 324 qualified
- Half bridge power module
- 650V blocking voltage
- Fast recovery body diode
- Very low switching energies
- Low package inductance
- Dice on direct bond copper(DBC) substrate
- Low thermal resistance

Applications

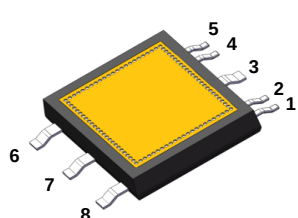
- Switching applications

Product Summary

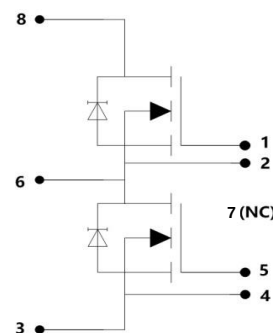
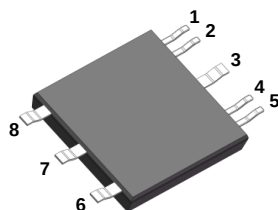
V _{DS}	650V
R _{DS(on)_typ}	41mΩ
I _D	62A

100% DVDS Tested

100% Avalanche Tested



CRJMH74M65EMAQ



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRJMH74M65EMAQ	CRJMH74M65EMAQ	MSOP8	Tape&Reel	N/A	N/A	200pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	650	V
Continuous drain current ¹⁾	I _D	62	A
T _C = 25°C			
T _C = 100°C		39	A
Pulsed drain current ²⁾ (T _C = 25°C, t _p limited by T _{jmax})	I _{D pulse}	250	A
Avalanche energy, single pulse (L=30mH, R _g =30Ω)	E _{AS}	1500	mJ
MOSFET dv/dt ruggedness	dv/dt	50	V/ns
Gate-Source voltage	V _{GS}	±30	V
Power dissipation (T _C = 25°C)	P _{tot}	424	W
Continuous diode forward current(T _C = 25°C)	I _S	62	A
Diode pulse current ²⁾ (T _C = 25°C)	I _{S pulse}	250	A
Recovery diode dv/dt ³⁾	dv/dt	50	V/ns
Maximum diode commutation speed	di _F /dt	900	A/μs
Operating junction and storage temperature	T _j , T _{stg}	-55...+150	°C

1) Limited by T_{j,max}. Maximum Duty Cycle D = 0.50;

2) Pulse width t_p limited by T_{j,max}

3) Identical low side and high side switch with identical R_G

Thermal Resistance

Parameter	Symbol	Unit			Unit
		min.	typ.	max.	
Thermal resistance, junction – case	R_{thJC}		0.295	0.34	°C/W
Thermal resistance, junction – ambient	R_{thJA}		24.67	28.37	°C/W

Electrical Characteristic (at $T_j = 25\text{ }^{\circ}\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV_{DSS}	650	-	-	V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	3	-	4.8	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Zero gate voltage drain current	I_{DSS}	-	-	5	μA	$V_{DS}=650V, V_{GS}=0V$ $T_j=25^{\circ}\text{C}$
		-	1000	-		$T_j=150^{\circ}\text{C}$
Gate-source leakage current	I_{GSS}	-	-	± 100	nA	$V_{GS}=\pm 30V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	41	50	mΩ	$V_{GS}=10V, I_D=35A,$ $T_j=25^{\circ}\text{C}$
		-	110	-		$T_j=150^{\circ}\text{C}$
Transconductance	g_{fs}	-	44	-	S	$V_{DS}=20V, I_D=35A$

Dynamic Characteristic

Input Capacitance	C _{iss}		6520		pF	V _{GS} =0V, V _{DS} =100V, f=1MHz
Output Capacitance	C _{oss}		260			
Reverse Transfer Capacitance	C _{rss}		2.4			
Gate Total Charge	Q _G		178		nC	V _{GS} =10V, V _{DS} =480V, I _D =35A
Gate-Source charge	Q _{gs}		56			
Gate plateau voltage	Q _{gd}		93			
Gate-Drain charge	V _{plateau}	-	8	-	V	
Turn-on delay time	t _{d(on)}	-	51	-	ns	V _{GS} =10V, I _D =35A, V _{DS} =400V, R _g =4.7Ω
Rise time	t _r	-	52	-		
Turn-off delay time	t _{d(off)}	-	112	-		
Fall time	t _f	-	9	-		
Gate resistance	R _G		1.2		Ω	V _{GS} =0V, V _{DS} =0V, f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	0.7	0.9	1.2	V	$V_{GS}=0V, I_{SD}=35A$
Body Diode Reverse Recovery Time	t_{rr}	-	195		ns	$I_{SD}=35A$ $dI/dt=100A/\mu s$ $V_{DS}=400V$
Body Diode Reverse Recovery Charge	Q_{rr}	-	1.5		μC	
Body Diode Reverse Recovery Peak Current	I_{rrm}	-	15		A	

Typical Performance Characteristics

Fig 1. Output Characteristics ($T_j=25^\circ\text{C}$)

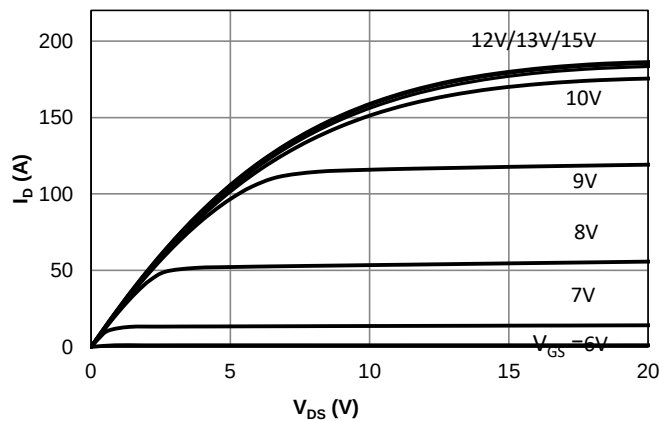


Fig 2. Output Characteristics ($T_j=150^\circ\text{C}$)

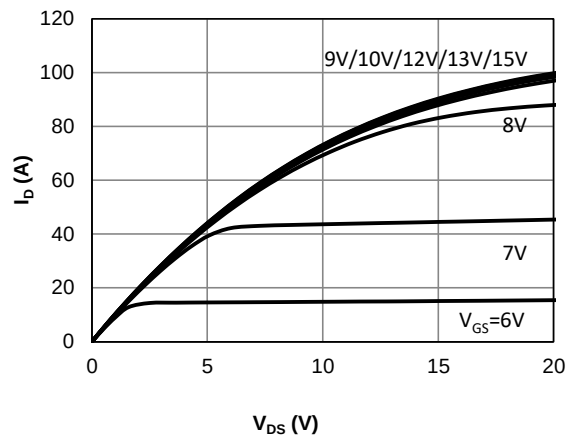


Fig 3: Transfer Characteristics

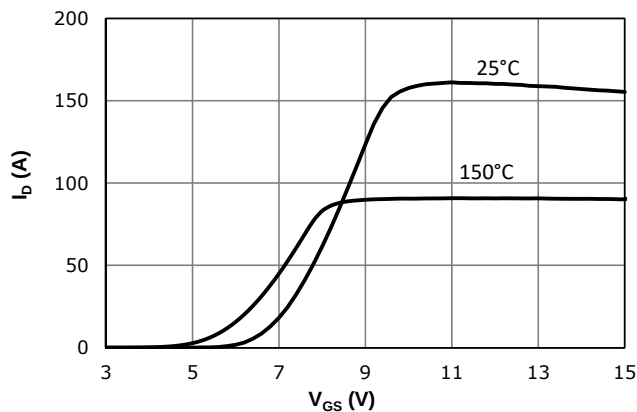


Fig 4: $V_{GS(TH)}$ Vs T_j Temperature Characteristics

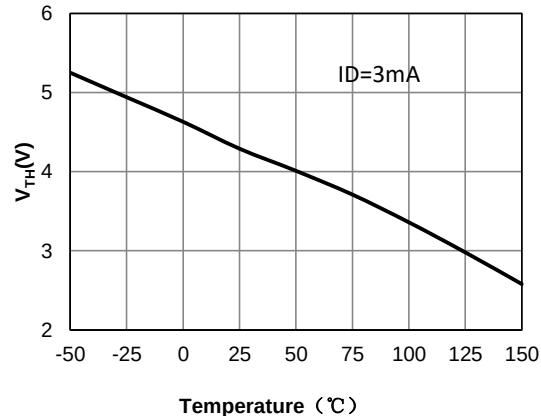


Fig 5: $R_{DS(on)}$ Vs I_{DS} Characteristics ($T_c=25^\circ\text{C}$)

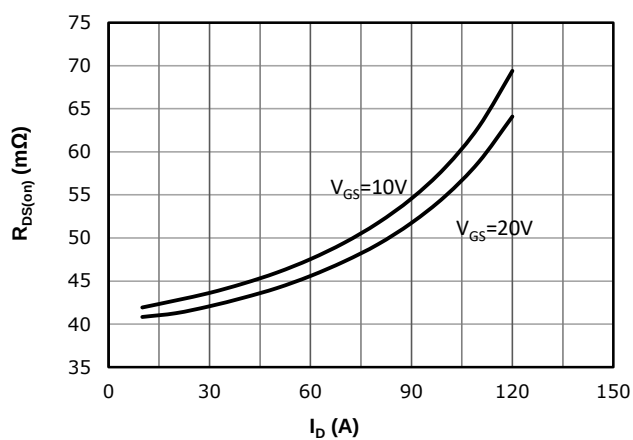


Fig 6: $R_{DS(on)}$ vs. Temperature

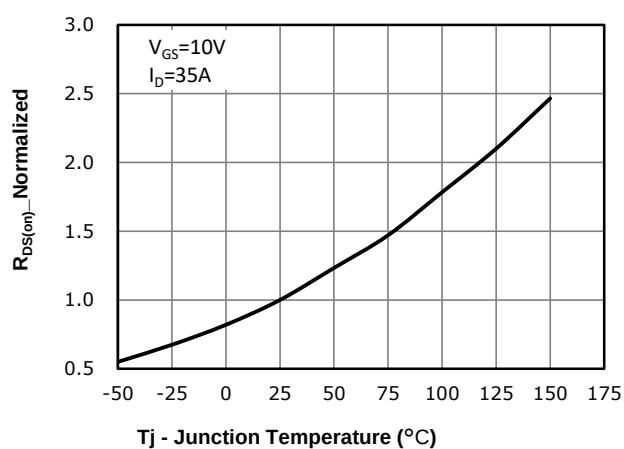


Fig 7: BVDSS vs. Temperature

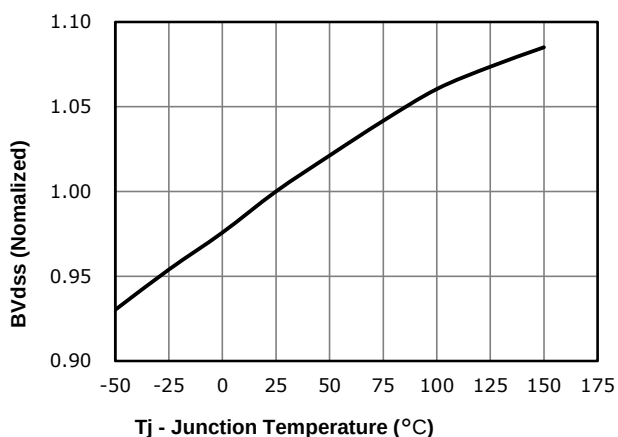


Fig 8: Rds(on) vs Gate Voltage

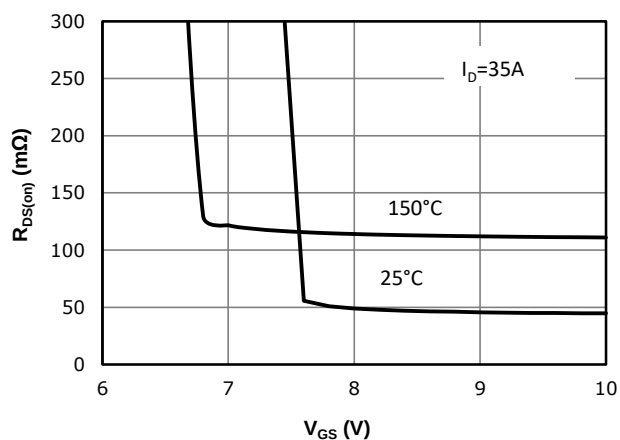


Fig 9: Body-diode Forward Characteristics

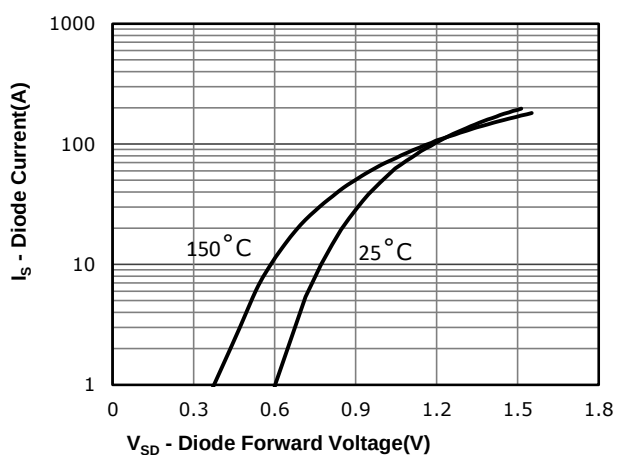


Fig 10: Gate Charge Characteristics

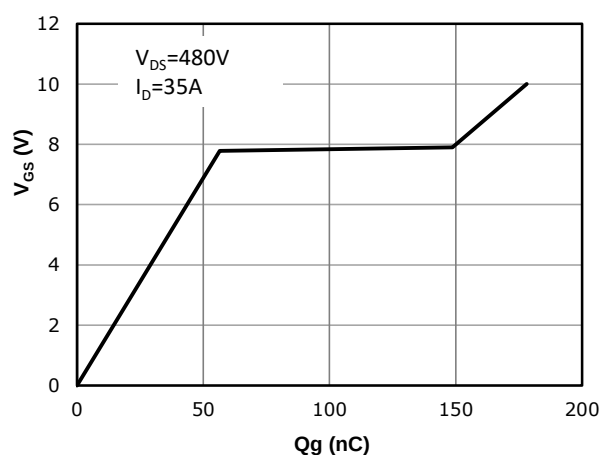


Fig 11: Capacitance Characteristics

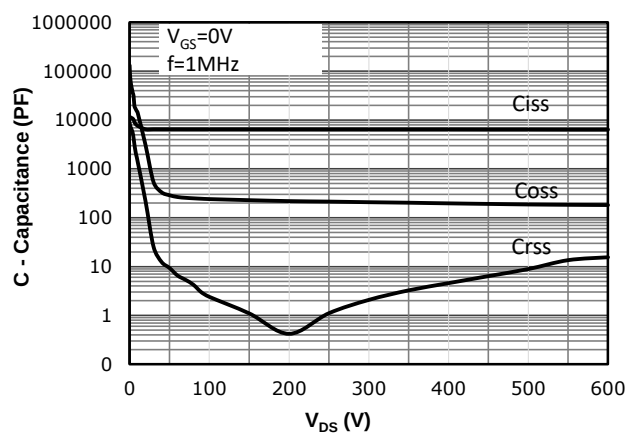


Fig 12: Safe Operating Area

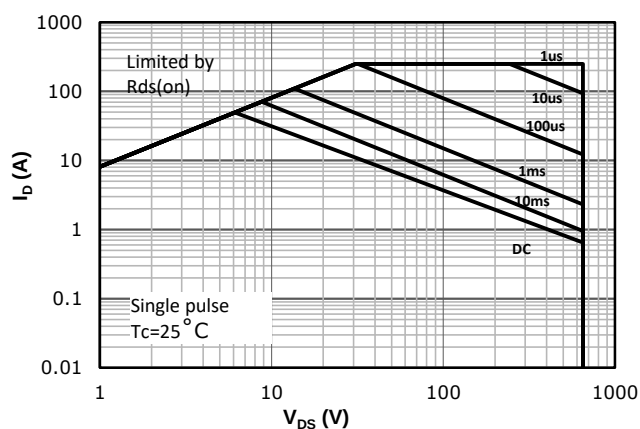
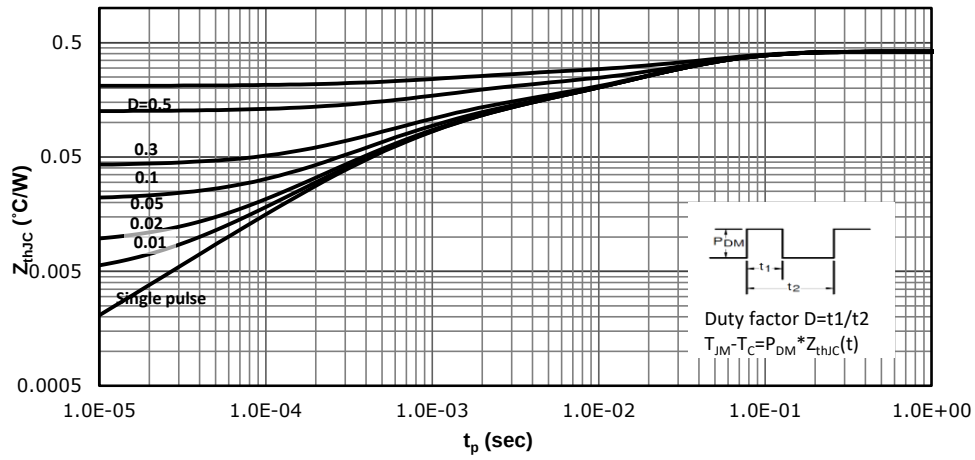
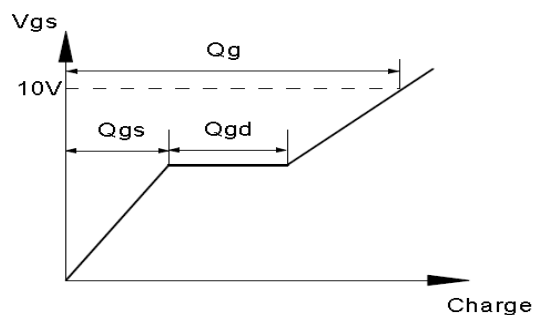
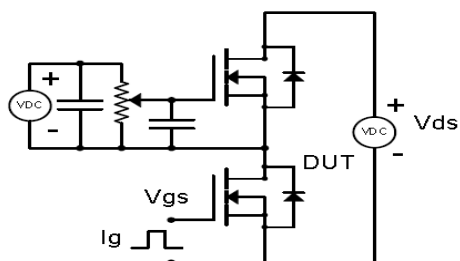


Fig 13: Max. Transient Thermal Impedance

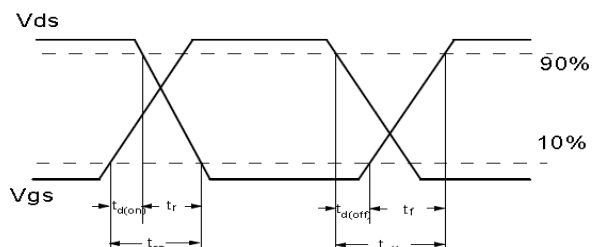
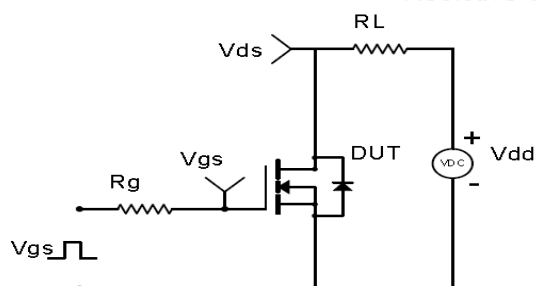


Test Circuit & Waveform

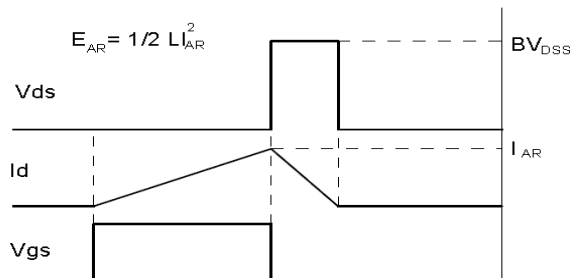
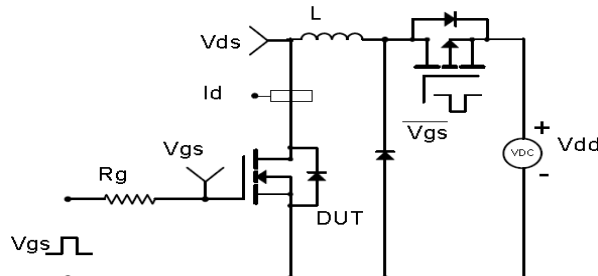
Gate Charge Test Circuit & Waveform



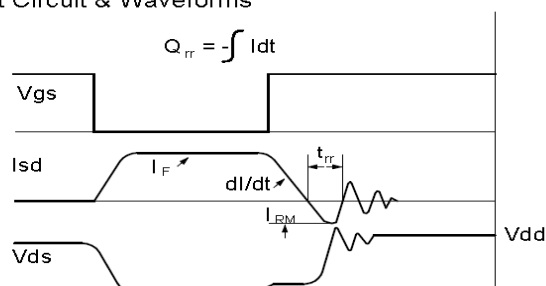
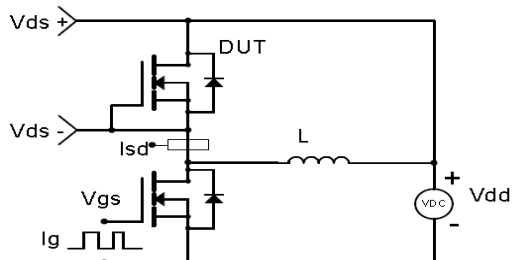
Resistive Switching Test Circuit & Waveforms



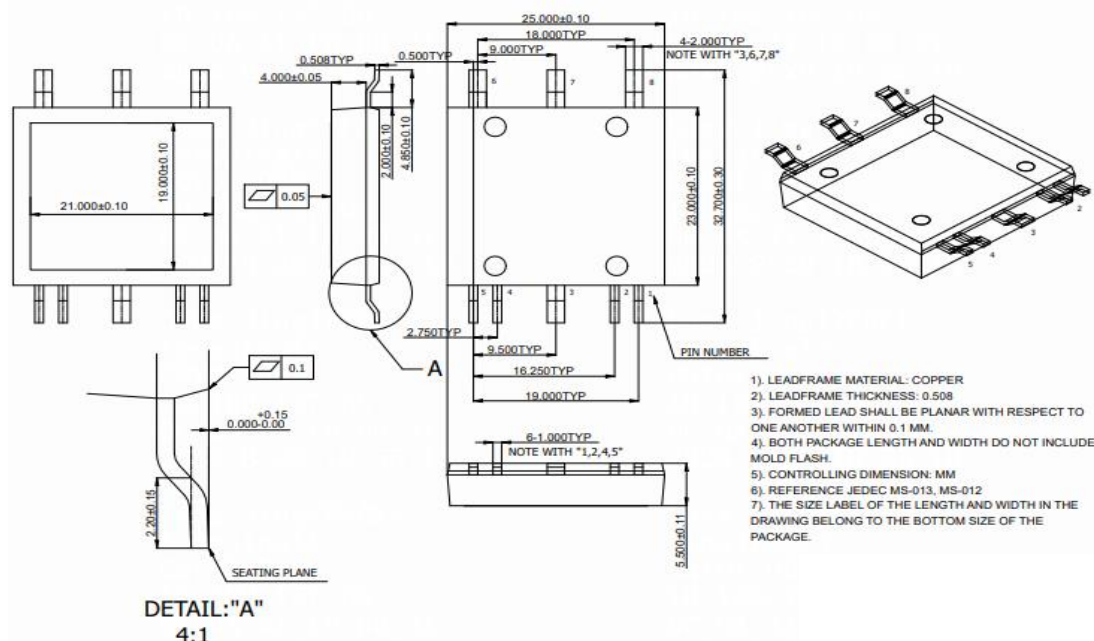
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: MSOP8



Revision History

Revision	Major changes
V1.0	Initial release
V2.0	Notice AQG 324 qualified
V3.0	Update package

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